

## RCX081N20-VB Datasheet N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	200			
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	0.265		
Q <sub>g</sub> (Max.) (nC)	16			
Q <sub>gs</sub> (nC)	5			
Q <sub>gd</sub> (nC)	8			
Configuration	Single			

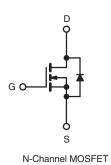
#### **FEATURES**

- · Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz



- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available





ABSOLUTE MAXIMUM RATINGS T	<sub>C</sub> = 25 °C, unless otherw	rise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	$V_{DS}$	200	V		
Gate-Source Voltage	$V_{GS}$	± 20	_ v		
Continuous Drain Current	$V_{GS}$ at 10 V $T_C = 25 ^{\circ}C$		10		
	$V_{GS}$ at 10 $V_{C} = 100 ^{\circ}C$	l <sub>D</sub>	6.5	Α	
Pulsed Drain Current <sup>a</sup>	I <sub>DM</sub>	32			
Linear Derating Factor			0.24	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>		E <sub>AS</sub>	36	mJ	
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	7.2	Α		
Repetitive Avalanche Energy <sup>a</sup>		E <sub>AR</sub>	3.7	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	37	W	
Peak Diode Recovery dV/dtc		dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF IVIS SCIEW		1.1	N⋅m	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}$  = 25 V, starting  $T_J$  = 25 °C, L = 1.0 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AS}$  = 7.2 A (see fig. 12). c.  $I_{SD} \le 9.2$  A,  $dI/dt \le 110$  A/µs,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175$  °C.
- d. 1.6 mm from case.

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	4.1	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	200	-	-	٧	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.13	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Zana Oata Wallana Busin Oamani		V <sub>DS</sub> =	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V		-	25	,. ^
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =160 V	, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4.3 A <sup>b</sup>	-	0.265	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 4.3 A <sup>b</sup>		-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$ $f = 1.0 \text{ MHz}$		-	560	-	
Output Capacitance	C <sub>oss</sub>			-	260	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	110	-	pF
Drain to Sink Capacitance	С			-	12	-	
Total Gate Charge	Qg		I <sub>D</sub> = 9.2 A, V <sub>DS</sub> = 80 V, see fig. 6 and 13 <sup>b</sup>	-	-	16	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	4.4	
Gate-Drain Charge	$Q_{gd}$	1		-	-	7.7	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 100 \text{ V, } I_{D} = 9.2 \text{ A,}$ $R_{G} = 18 \Omega, R_{D} = 5.2 \Omega,$ see fig. $10^{b}$		-	8.8	-	- ns
Rise Time	t <sub>r</sub>			-	30	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	19	-	
Fall Time	t <sub>f</sub>			-	20	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		=	4.5	-	
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s				•		
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	10	-	A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	32	-	^
Body Diode Voltage	$V_{SD}$	$T_J$ = 25 °C, $I_S$ = 7.2 A, $V_{GS}$ = 0 $V^b$		-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25  ^{\circ}\text{C}, \ I_F = 9.2  \text{A}, \ \text{dI/dt} = 100  \text{A/}\mu\text{s}^b$		-	130	260	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.65	1.3	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> a				$L_S$ and I	)

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

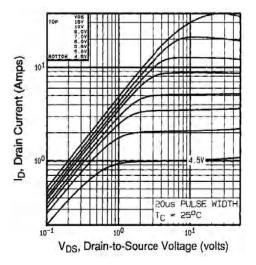


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

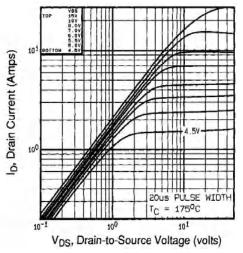


Fig. 2 - Typical Output Characteristics,  $T_C = 175$  °C

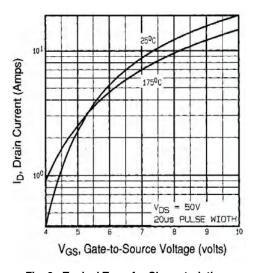


Fig. 3 - Typical Transfer Characteristics

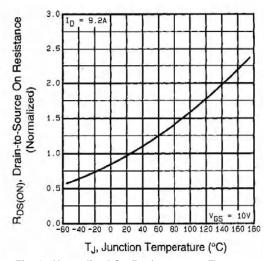


Fig. 4 - Normalized On-Resistance vs. Temperature

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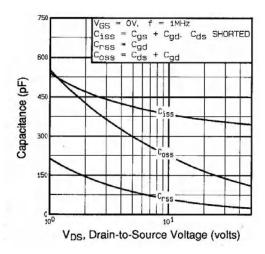


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

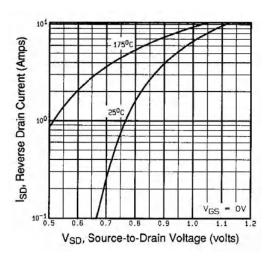


Fig. 7 - Typical Source-Drain Diode Forward Voltage

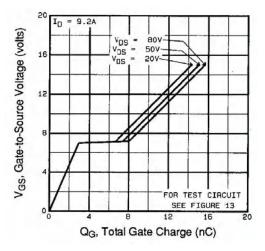


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

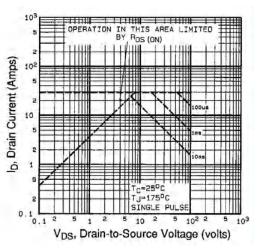


Fig. 5 - Fig. 8 - Maximum Safe Operating Area



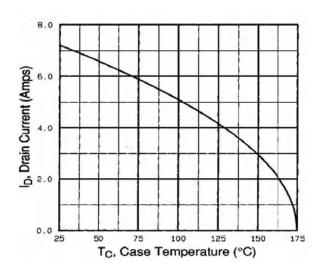


Fig. 9 - Maximum Drain Current vs. Case Temperature

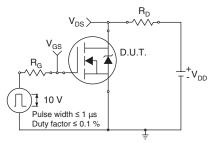


Fig. 10a - Switching Time Test Circuit

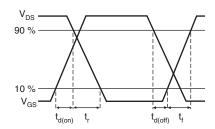


Fig. 10b - Switching Time Waveforms

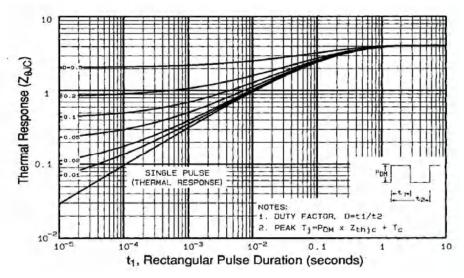


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

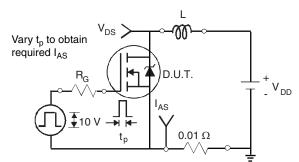


Fig. 12a - Unclamped Inductive Test Circuit

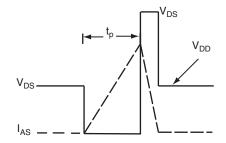
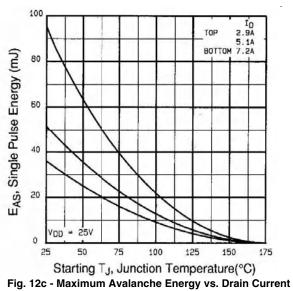


Fig. 12b - Unclamped Inductive Waveforms





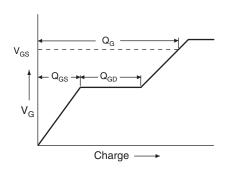


Fig. 13a - Basic Gate Charge Waveform

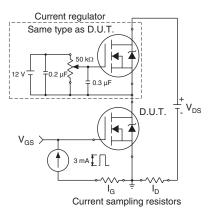
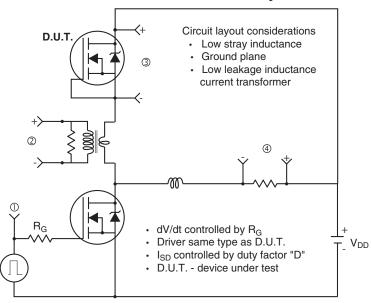


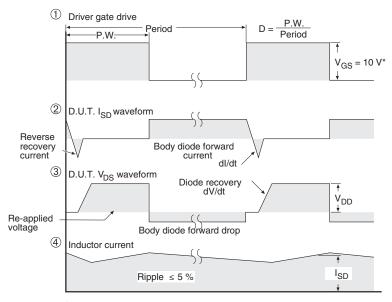
Fig. 13b - Gate Charge Test Circuit

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### Peak Diode Recovery dV/dt Test Circuit





\*  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel

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